

Search Notes

Application/Control No.

10/827,231

Examiner

Chuck Mah

Applicant(s)/Patent under
Reexamination

HSIEH, JASON

Art Unit

3677

SEARCHED

Class	Subclass	Date	Examiner
16	337-341		
	303		
	330		
403	146		
	150		
	153-156		
361	680-683		
248	919-923		
		7/23/5 <i>exp</i>	

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR